

Notice of References Cited

 Application/Control No.
 09/765,430

 Applicant(s)/Patent Under Reexam
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Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY ¹	Name	Classification ²	
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NON-PATENT DOCUMENTS

*	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages		
x U	Austin et al, "Efficient detection of all pointers and arrays access errors", SIGPLAN ACM, pp 290-301		
x V	Edelson, "A mark and sweep collector for C + + ", ACM pp 51-58		
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x X	Jarvinen et al, "Object oriented specification of reactive systems", IEEE, pp 63-71		

* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

¹ Dates in MM-YYYY format are publication dates.

² Classifications may be U.S. or foreign.